

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Yoel ARIELI, et al.

Serial No.: 09/829,435

Group No.: 2877

Filed: April 9, 2001

Examiner:

For: SPATIAL AND SPECTRAL WAVEFRONT ANALYSIS
AND MEASUREMENT

Attorney Docket No.: U 013396-8

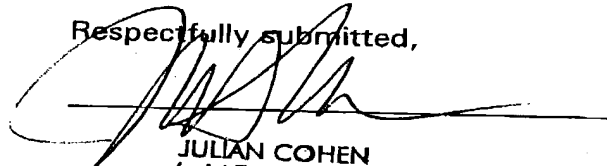
Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

Sir:

FACSIMILE NO.: 703-305-4372
ATTN: Bernadette Queen**NO. OF PAGES:** 4

As requested enclosed is the 1449 of December 10, 2001.

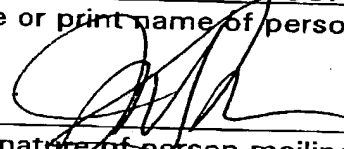
Respectfully submitted,

JULIAN COHEN
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Date December 10, 2001

Page 1 of 3

FORM PTO-1449 (Rev. 10-01)

ATTY DOKUMENT NO
1-403596-8SERIAL NUMBER
09829435LIST OF PATENTS AND PUBLICATIONS
FOR APPLICANT'S INFORMATION
STATEMENTAPPLICANT
Yoshinori U. et alFILING DATE
April 9, 2001GROUP PART I (SII)
2877

U.S. PATENT DOCUMENTS

Examiner's Initials	DOCUMENT NO	DATE	NAME	CLASS	SUB	FILING DATE
ab	AA	5,969,854	Oct 1999	Ishiwata, et al	359	386
	AB	5,969,853	Oct 1999	Takaoka	359	370
	AC	5,936,253	Aug 1999	Nugaya	250	548
	AD	5,870,191	Feb 1999	Shirley, et al	343	356
	AE	5,814,815	Sep 1998	Matsumoto et al	250	311
	AF	5,751,475	May 1998	Ishiwata, et al	359	387
	AG	5,619,372	Apr 1997	Hellmuth et al	339	289
	AH	5,600,440	Feb 1997	Bendall	356	345

FOREIGN PATENT DOCUMENTS

	DOCUMENT NO	DATE	COUNTRY	CLASS	SUB	TRANSLATION
↓	AI	JP 9230247	4/1997	Japan		
	AJ	JP 9150020	7/1997	Japan		
↓	AK	JP 8004936	4/1996	Japan		

OTHER ARTS OF INVENTION: None (see pages 1-2)

- AI Philion DW "General Methods for Generating Phase-Shifting Interferometry Algorithms" Applied Optics Vol. 36, 8008 (1997)
- ↓
- AMI Phila M "Stray-Light Problem in Phase Contrast Microscope or Toward Highly Sensitive Phase Contrast Devices: A review" Optical Engineering Vol. 32, 3109

EXAMINER: *[Signature]* DATE CONSIDERED: 12/16/01

EXAMINER: If a reference is considered whether or not citation is in conformance with MPEP 600.1. If not, cite through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date December 4, 2001

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FORM PTO-1449 (C50b)

ATTY DCKET NO
1.0133068SERIAL NUMBER
09 829,435LIST OF PATENTS AND PUBLICATIONS
FOR APPLICANT'S INFORMATION
STATEMENTAPPLICANT
Yael ARIEU, et al

FILING DATE

April 9, 2001

GROUP PART UNIT

2977

U.S. PATENT DOCUMENTS

Examiner's Initials		DOCUMENT NO	DATE	NAME	CLASS	SUB	FILING DATE
SC	AA	5,159,474	Oct 1992	Franke, et al	359	29	
	AB	5,777,736	Jul 1998	Horton	356	346	
	AC	4,653,921	Mar 1987	Kwon	356	353	
	AD						
	AE						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO	DATE	COUNTRY	CLASS	SUB	TRANS- LATION
SM	AF	1-PD 555,099	8/1993	Europe			
SM	AG	GB 2,315,700	2/1998	Great Britain			
	AH						

OTHER ART (including prior art) Pertinent Pages (s)

SM	AI	Goldenfeld, "Zernike Test: Analytical Aspects" Applied Optics, Vol. 16, 205 (1977)
SM	AJ	Bruning J H, et al, "Digital Wavefront Measuring Interferometry for Testing Optical Surfaces and Lenses", Applied Optics, Vol. 13, 2693 (1974)
	AK	
	AL	

EXAMINER

DATE CONSIDERED

11/16/03

EXAMINER

Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Page 2 of 3

FORM PTO-1449 (CGB)

ATTY DCKET NO

SERIAL NUMBER

1-013396-X

00829433

LIST OF PATENTS AND PUBLICATIONS
FOR APPLICANT'S INFORMATION
STATEMENTAPPLICANT
Yoel ARIEU, et al

FILING DATE

GROUP PARTIAL NO

April 9, 2001

2877

U.S. PATENT DOCUMENTS

Examiner's Initials	DOCUMENT NO	DATE	NAME	CLASS	SUB	FILING DATE
sk	AA	5,171,503	Nov 1993	Ar et al	356	257
	AB	5,446,540	Aug 1995	Lin	356	345
	AC	5,235,587	Apr 1993	Bearden, et al	369	106
	AD	4,407,569	Oct 1983	Piller, et al	350	509
	AE	1,190,366	Feb 1980	Doyle	356	346

FOREIGN PATENT DOCUMENTS

	DOCUMENT NO	DATE	COUNTRY	CLASS	SUB	TRANSLATION
sk	AF	JP 7261089	10/1995	Japan		
	AG	JP 7334341	8/1995	Japan		
	AH	JP 6186504	7/1994	Japan		

OTHER ART (including Author Title Position Pages Date)

sk	AI	Noda T. and Kawata S. "Separation of Phase and Absorption Images in Phase-contrast Microscopy". Journal of the Optical Society of America A, Vol. 9, 924 (1992).
	AJ	Creath K. "Phase Measurement Interferometry Techniques". Progress in Optics XXVI, 348 (1988).
	AK	Groeninkamp J. "Generalized Data Reduction for heterodyne Interferometry". Optical Engineering, Vol. 23, 357 (1984).
	AL	Morgan C. J. "Least Squares Estimation in Phase-Measurement Interferometry". Optics Letters, Vol. 7, 568 (1982).

EXAMINER

DATE CONSIDERED

4/16/03

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Date: December 10, 2001

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FORM PTO-1449 (Colb)	ATTY DOCKET NO. U-013396-8	SERIAL NUMBER 09/829,435
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS' INFORMATION STATEMENT	APPLICANT Yoel ARIELI, et al.	
	FILING DATE April 9, 2001	GROUP ART UNIT 2877

U.S. PATENT DOCUMENTS

Examiner's Initials		DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
	AA	5,969,855	Oct. 1999	Ishiwata, et al.	359	386	
	AB	5,969,853	Oct. 1999	Takaoka	359	370	
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	AH	5,600,440	Feb. 1997	Bendall	356	345	

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	AI	JP 9230247	9/1997	Japan			
	AJ	JP 9179029	7/1997	Japan			
	AK	JP 8094936	4/1996	Japan			

OTHER ART (Including Author, Bills, Pertinent Pages, Etc.)

AL	Phillion D.W. "General Methods for Generating Phase-Shifting Interferometry Algorithms", Applied Optics, Vol. 36, 8098 (1997).
AM	Pluta M., "Stray-Light Problem in Phase Contrast Microscopy or Toward Highly Sensitive Phase Contrast Devices: A review", Optical engineering, Vol. 32, 3199 (1993).
EXAMINER:	
DATE CONSIDERED:	
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Page 2 of 3

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	AC	5,235,587	Apr. 1993	Bearden, et al.	369	106	
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	AE	4,190,366	Feb. 1980	Doyle	356	346	

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	AG	JP 7225341	8/1995	Japan			
	AH	JP 6186504	7/1994	Japan			

OTHER ART (Including Author, Bills, Pertinent Pages, Etc.)

AI	Noda T. and Kawata S., "Separation of Phase and Absorption Images in Phase-Contrast Microscopy", Journal of the Optical Society of America A, Vol. 9, 924 (1992).
AJ	Creath K., "Phase Measurement Interferometry Techniques", Progress in Optics XXVI, 348 (1988).
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AL	Morgan C.J. "Least-Squares Estimation in Phase-Measurement Interferometry", Optics Letters, Vol. 7, 368 (1982).
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	AB	5,777,736	Jul. 1998	Horton	356	346	
	AC	4,653,921	Mar. 1987	Kwon	356	353	
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	AE						

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		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB	TRANS- LATION
	AF	EP 0 555 099	8/1993	Europe			
	AG	GB 2,315,700	2/1998	Great Britain			
	AH						

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AI	Golden L.J. "Zemike Test. 1: Analytical Aspects" - Applied Optics, Vol. 16, 205 (1977).
AJ	Bruning J.H. et al., "Digital Wavefront Measuring Interferometry for Testing Optical Surfaces and Lenses", Applied Optics, Vol. 13, 2693 (1974).
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